

**Giancarlo Pepponi** currently coordinates the Reserach and Development activities of the Micro-Nano fabrication and characterization Facility (MNF) of the Centre for Sensors and Devices, Fondazione Bruno Kessler, Trento Italy. After having graduated in Physics at the University of Trento (1999) he earned a PhD in technical physics at the Vienna University of Technology (2003) defending a thesis with title “Synchrotron Radiation induced Total Reflection X-Ray Fluorescence Analysis applied to Material Science”. He is author and co-author of over 100 articles in refereed journals mostly related to X-Ray Spectrometry for elemental analysis and materials characterisation where his contributions involved both the experimental and the computational (data evaluation) activities. Recent research interests involve the combination of analytical techniques (e.g. combined XRF and XRD analysis), the design and testing of semiconductor detectors for specific analytical needs and applications, the development chemoresistive gas sensors, the development and exploitation of nano-fabrication and nano-characterization techniques in the above mentioned fields.